

SEM 2013

October 15-17, 2013, Göteborg, SWEDEN

Tuesday October 15, 2013

08.45 - 09.00 **Registration: outside Kollektorn**

09.00 - 12.15 **LECTURE HALL Kollektorn**

09.00 - 09.20 Welcome address and introductory remarks by the organizers
Peter Apell, Head of Department, Applied Physics, Chalmers
Lena Falk and Mats Halvarsson, Applied Physics, Chalmers

09.20 - 10.00 Technological solutions in the scanning electron microscope
Mats Eriksson, Spectral Solutions, Sweden

10.00 - 10.30 **COFFEE in the Canyon**

10.30 - 11.10 An introduction to XEDS in the SEM
Mathias Procop, IfG-Institute for Scientific Instruments, Berlin

11.15 - 11.55 Quantitative analysis by XEDS
Simon Burgess, Oxford Instruments, UK

11.55 - 13.00 **LUNCH in the Canyon**

13.00 - 19.00 **PRACTICALS**

13.00 - 14.15 Demonstrations -- Session I

14.15 - 14.45 **COFFEE in the Canyon**

14.45 - 17.15 Demonstrations -- Session II

17.15 - 19.00 Open Lab

19.00 **COURSE DINNER in the Canyon**

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Wednesday October 16, 2013

09.00 - 12.00 *LECTURE HALL KOLLEKTORN*

09.00 - 09.10 Introductory remarks by the organizers

09.10 - 09.45 High resolution SEM at low voltages
Emanuel Katzmann, Jeol (Germany) GmbH

09.45 - 10.15 **COFFEE in the Canyon**

10.15 - 10.45 Sample preparation for SEM and XEDS
Julia Netrval, Spectral Solutions, Sweden

10.45 - 11.20 The requirements on a modern XEDS system
Mathias Procop, IfG-Institute for Scientific Instruments, Berlin

11.20 - 11.25 **BREAK**

11.25 - 12.00 3D applications in dual beam instruments
Ellen Bakken, FEI Company, The Netherlands

12.00 - 13.00 **LUNCH in the Canyon**

13.00 - 20.00 *PRACTICALS*

13.00 - 14.15 Demonstrations -- Session III

14.15 - 14.45 **COFFEE in the Canyon**

14.45 - 16.00 Demonstrations -- Session IV

16.00 **SANDWICHES and REFRESHMENTS**

16.00 - 20.00 Open Lab

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Thursday October 17, 2013

09.00 - 12.00 *LECTURE HALL KOLLEKTORN*

09.00 - 09.05 Introductory remarks by the organizers

09.05 - 09.40 Correlative microscopy - combined LM and SEM

Michael Andersson, Carl Zeiss AB, Sweden

09.40 - 10.15 Combined XEDS and XRF analysis in the SEM

Mathias Procop, IfG-Institute for Scientific Instruments, Berlin

10.15 - 10.45 **COFFEE in the CANYON**

10.45 - 11.20 X-ray WDS and EDS - a comparison

Simon Burgess, Oxford Instruments, UK

11.20 - 11.50 Panel discussion

11.50 - 12.00 Concluding remarks by the organizers

12.00 - 13.00 **LUNCH in the CANYON**

13.00 - 15.30 *PRACTICALS*

13.00 - 14.15 Demonstrations -- Session V

14.15 - 14.30 **COFFEE in the CANYON**

14.30 - 15.45 Demonstrations -- Session VI

15.45 *End of Course*